

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: **Makoto HASEYAMA**

Serial Number: **Not Yet Assigned**

Filed: **October 3, 2003**

Customer No.: 38834

For: **CONTACTOR APPARATUS FOR SEMICONDUCTOR DEVICES AND A TEST METHOD OF SEMICONDUCTOR DEVICES**

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

October 3, 2003

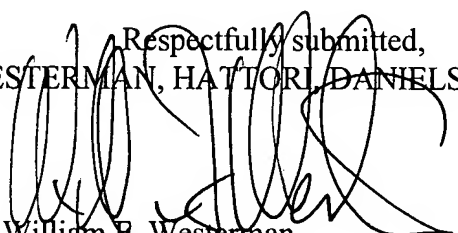
Sir:

In compliance with 37 CFR 1.56, Applicant calls to the attention of the Patent and Trademark Office the references listed on the attached PTO-1449. References AE - AH are cited in the enclosed international search report.

A copy of each of the references is enclosed herewith, except for the U.S. references.

In the event there are any fees due in connection with the filing of this paper, please charge Deposit Account No. 50-2866.

Respectfully submitted,
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Enclosures: PTO-1449; References (5) and international search report.

INFORMATION DISCLOSURE STATEMENT PTO-1449	Atty. Docket No. 032003	Serial No. New Appln.
	Applicant(s): Makoto HASEYAMA	
	Filing Date: October 3, 2003	Group Art Unit:

U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Name	Date	Class	Subclas s	Filing Date (If appropriate)
	AA	5,825,192	J. Hagiwara	1/20/98			
	AB	6,130,543	Shinji Iino	10/10/00			
	AC						
	AD						

FOREIGN PATENT DOCUMENTS

		Document No.	Date	Country	Translation (Yes or No)
	AE	63-84946	06/03/88	Japan	Abstract. Cited in the int'l. search rpt.
	AF	10-223704	08/21/98	Japan	Abstract. Cited in the int'l. search rpt.
	AG	62-11243	01/20/87	Japan	Abstract. Cited in the int'l. search rpt.
	AH	63-57745	04/18/88	Japan	Partial. Cited in the int'l. search rpt.
	AI	7-130802	05/19/95	Japan	Abstract.

OTHER DOCUMENTS

	AJ	
	AK	
Examiner	Date Considered	